

BSW 93

HIGH VOLTAGE, HIGH CURRENT SWITCH

PNP DIFFUSED SILICON PLANAR EPITAXIAL TRANSISTOR

- FAST SWITCHING..... $t_{on} = 25\text{ns}$, $t_{off} = 65\text{ns}$ AT 500mA
- LOW SATURATION VOLTAGE..... $V_{CEsat} = 0.5\text{V}$ (MAX) AT 500mA
- HIGH FREQUENCY..... $f_T = 230\text{MHz}$ (TYP) AT 50mA
- GAIN SPECIFIED.....THREE POINTS 100mA TO 1A

ABSOLUTE MAXIMUM RATINGS (Note 1)

Maximum Temperatures

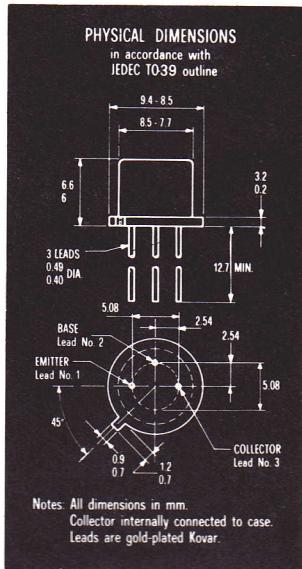
T_{STG}	Storage Temperature Range	-55°C to 200°C
T_J	Operating Junction Temperature	200°C
T_L	Lead Temperature (Soldering, 10 s time limit)	260°C

Maximum Power Dissipations (Notes 2 and 3)

P_D	Total Dissipation at 25°C Case Temperature	4 W
	at 25°C Ambient Temperature	1 W

Maximum Voltages and Current (25°C free air temperature)

V_{CBO}	Collector to Base Voltage	-30 V
V_{CEO}	Collector to Emitter Voltage (Note 4)	-30 V
V_{EBO}	Emitter to Base Voltage	-5 V
I_C	Collector Current	1 A



ELECTRICAL CHARACTERISTICS (25°C free air temperature unless otherwise noted)

SYMBOL	CHARACTERISTIC	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
h_{FE}	DC Current Gain (Note 5)	15.....45.....			$I_C = 100 \text{ mA}$	$V_{CE} = -1 \text{ V}$
h_{FE}	DC Current Gain (Note 5)	25.....50.....			$I_C = 500 \text{ mA}$	$V_{CE} = -1 \text{ V}$
h_{FE}	DC Current Gain (Note 5)	25.....50.....			$I_C = 1 \text{ A}$	$V_{CE} = -5 \text{ V}$
$h_{FE} (-55^\circ\text{C})$	DC Current Gain (Note 5)	10.....30.....			$I_C = 500 \text{ mA}$	$V_{CE} = -1 \text{ V}$
V_{BEsat}	Base Saturation Voltage (Note 5)	-0.9....-1.1....	V		$I_C = 100 \text{ mA}$	$I_B = 10 \text{ mA}$
V_{BEsat}	Base Saturation Voltage (Note 5)	-1.1....-1.5....	V		$I_C = 500 \text{ mA}$	$I_B = 50 \text{ mA}$
V_{BEsat}	Base Saturation Voltage (Note 5)	-1.3....-1.9....	V		$I_C = 1 \text{ A}$	$I_B = 100 \text{ mA}$
V_{CEsat}	Collector Saturation Voltage (Note 5)	-0.15....-0.25....	V		$I_C = 100 \text{ mA}$	$I_B = 10 \text{ mA}$
V_{CEsat}	Collector Saturation Voltage (Note 5)	-0.25....-0.5....	V		$I_C = 500 \text{ mA}$	$I_B = 50 \text{ mA}$
V_{CEsat}	Collector Saturation Voltage (Note 5)	-0.4....-0.95....	V		$I_C = 1 \text{ A}$	$I_B = 100 \text{ mA}$
I_{CES}	Collector Reverse Current	10.....100.....	nA		$V_{CE} = -20 \text{ V}$	$V_{EB} = 0$
$I_{CES} (100^\circ\text{C})$	Collector Reverse Current	1.5.....15.....	μA		$V_{CE} = -20 \text{ V}$	$V_{EB} = 0$
BV_{CBO}	Collector to Base Breakdown Voltage	-30.....	V		$I_C = 100 \mu\text{A}$	$I_E = 0$

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SGS-FAIRCHILD: LONDON - MILAN - PARIS - STOCKHOLM - STUTTGART



- FAST SWITCHING..... $t_{on} = 25\text{ns}$, $t_{off} = 65\text{ns}$ AT 500mA
- LOW SATURATION VOLTAGE..... $V_{CEsat} = 0.5\text{V}$ (MAX) AT 500mA
- HIGH FREQUENCY..... $f_T = 230\text{MHz}$ (TYP) AT 50mA
- GAIN SPECIFIED.....THREE POINTS 100mA TO 1A

ABSOLUTE MAXIMUM RATINGS (Note 1)

Maximum Temperatures

T_{STG}	Storage Temperature Range	-55°C to 200°C
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Maximum Power Dissipations (Notes 2 and 3)

P_D	Total Dissipation at 25°C Case Temperature	4 W
	at 25°C Ambient Temperature	1 W

Maximum Voltages and Current (25°C free air temperature)

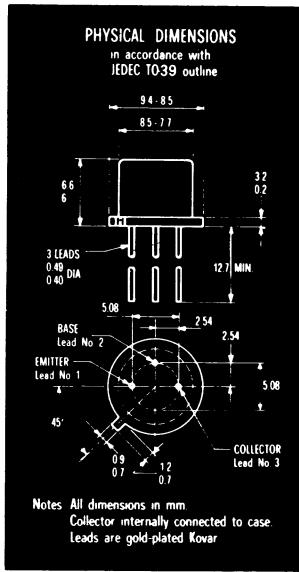
V_{CBO}	Collector to Base Voltage	-30 V
V_{CEO}	Collector to Emitter Voltage (Note 4)	-30 V
V_{EBO}	Emitter to Base Voltage	-5 V
I_C	Collector Current	1 A

ELECTRICAL CHARACTERISTICS (25°C free air temperature unless otherwise noted)

SYMBOL	CHARACTERISTIC	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
h_{FE}	DC Current Gain (Note 5)	15.....45.....			$I_C = 100\text{ mA}$	$V_{CE} = -1\text{ V}$
h_{FE}	DC Current Gain (Note 5)	25.....50.....			$I_C = 500\text{ mA}$	$V_{CE} = -1\text{ V}$
h_{FE}	DC Current Gain (Note 5)	25.....50.....			$I_C = 1\text{ A}$	$V_{CE} = -5\text{ V}$
h_{FE} (-55°C)	DC Current Gain (Note 5)	10.....30.....			$I_C = 500\text{ mA}$	$V_{CE} = -1\text{ V}$
V_{BEsat}	Base Saturation Voltage (Note 5)	-0.9....-1.1....	V		$I_C = 100\text{ mA}$	$I_B = 10\text{ mA}$
V_{BEsat}	Base Saturation Voltage (Note 5)	-1.1....-1.5....	V		$I_C = 500\text{ mA}$	$I_B = 50\text{ mA}$
V_{BEsat}	Base Saturation Voltage (Note 5)	-1.3....-1.9....	V		$I_C = 1\text{ A}$	$I_B = 100\text{ mA}$
V_{CEsat}	Collector Saturation Voltage (Note 5)	-0.15....-0.25....	V		$I_C = 100\text{ mA}$	$I_B = 10\text{ mA}$
V_{CEsat}	Collector Saturation Voltage (Note 5)	-0.25....-0.5....	V		$I_C = 500\text{ mA}$	$I_B = 50\text{ mA}$
V_{CEsat}	Collector Saturation Voltage (Note 5)	-0.4....-0.95....	V		$I_C = 1\text{ A}$	$I_B = 100\text{ mA}$
I_{CES}	Collector Reverse Current	10.....100.....	nA	$V_{CE} = -20\text{ V}$		$V_{EB} = 0$
I_{CES} (100°C)	Collector Reverse Current	1.5.....15.....	μA	$V_{CE} = -20\text{ V}$		$V_{EB} = 0$
BV_{CBO}	Collector to Base Breakdown Voltage	-30.....	V		$I_C = 100\text{ }\mu\text{A}$	$I_E = 0$

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SGS-FAIRCHILD: LONDON - MILAN - PARIS - STOCKHOLM - STUTTGART

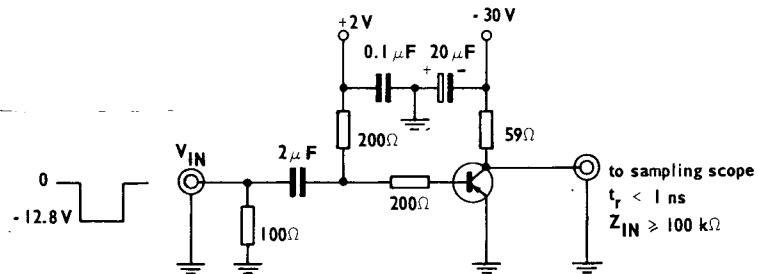


BSW 93 SGS-Fairchild Silicon Planar Transistor

ELECTRICAL CHARACTERISTICS (25°C free air temperature unless otherwise noted)

SYMBOL	CHARACTERISTIC	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
BV_{EBO}	Emitter to Base Breakdown Voltage.....	-5.....	V.....	$I_E = 100 \mu A$	$I_C = 0$	
LV_{CEO}	Collector to Emitter Sustaining.....	-30.....	V.....	$I_C = 10 \text{ mA}$	$I_B = 0$	
h_{fe}	High Frequency Current Gain.....	1.5.....	2.3.....	$I_C = 50 \text{ mA}$	$V_{CE} = -10 \text{ V}$ $f = 100 \text{ MHz}$	
C_{TE}	Emitter Transition Capacitance.....	80.....	100.....	pF.....	$I_C = 0$	$V_{EB} = -0.5 \text{ V}$ $f = 1 \text{ MHz}$
C_{obo}	Base-Collector Capacitance.....	20.....	25.....	pF.....	$I_E = 0$	$V_{CB} = -10 \text{ V}$ $f = 1 \text{ MHz}$
t_{on}	Turn On Time (Note 6).....	25.....	50.....	ns.....	$I_C \approx 500 \text{ mA}$	$I_{B1} \approx 50 \text{ mA}$
t_{off}	Turn Off Time (Note 6).....	65.....	100.....	ns.....	$I_C \approx 500 \text{ mA}$	$I_{B1} \approx 50 \text{ mA}$ $I_{B2} \approx 50 \text{ mA}$

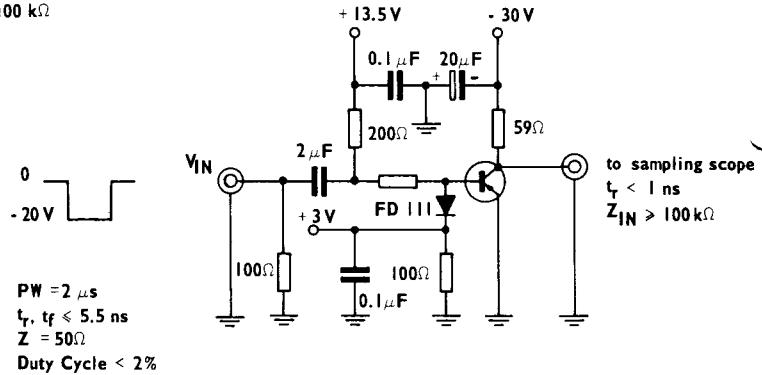
t_{on} TEST CIRCUIT



$t_r \leq 1 \text{ ns}$
 $PW = 250 \text{ ns}$
 $Z = 50 \Omega$
Duty cycle < 2%



t_{off} TEST CIRCUIT



$PW = 2 \mu s$
 $t_r, t_f \leq 5.5 \text{ ns}$
 $Z = 50 \Omega$
Duty Cycle < 2%

NOTES:

- (1) These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- (2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
- (3) These ratings give a maximum junction temperature of 200°C and junction-to-case thermal resistance of 43.8°C/W (derating factor of 22.8 mW/°C); junction-to-ambient thermal resistance of 175°C/W (derating factor of 5.7 mW/°C).
- (4) This rating refers to a high-current point where collector-to-emitter voltage is lowest. For more information send for SGS-Fairchild AR 5.
- (5) Measured under pulse conditions: pulse length = 300 μsec; duty cycle = 1%.
- (6) See switching circuits for exact values of I_C , I_{B1} and I_{B2} .